

# The ALICE ITS UPGRADE

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on behalf of the ALICE collaboration



# ALICE UPGRADE

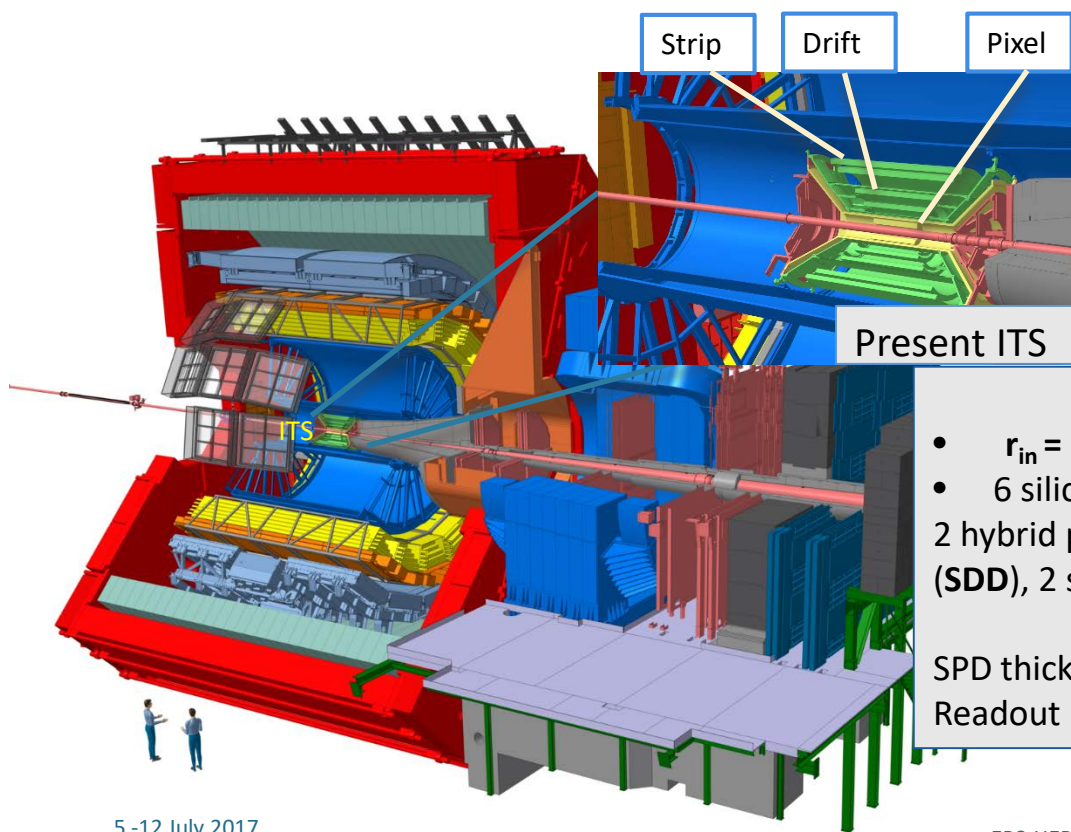
Major upgrade of ALICE foreseen during Long Shutdown 2 (2019/20)

Expected Run3&4 Pb-Pb luminosity  $6 \times 10^{27} \text{ cm}^{-2}\text{s}^{-1}$  ( $10 \text{ nb}^{-1}$  integrated, factor 100 gain in statistics wrt Run1-2)

**Physics Goal: Study of Quark Gluon Plasma properties via high-precision measurements of rare probes**

- identification of secondary vertex of short lived particles @ low  $p_T$
- large minimum bias data sample needed (no hardware trigger possible)

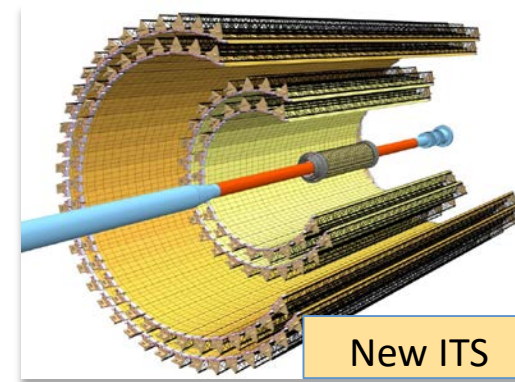
To cope with the increased luminosity and improve the tracking performances, several upgrades planned: new **Inner Tracking System**, new Muon Forward Tracker, TPC, Readout electronics, Trigger, Online/Offline



## Present ITS

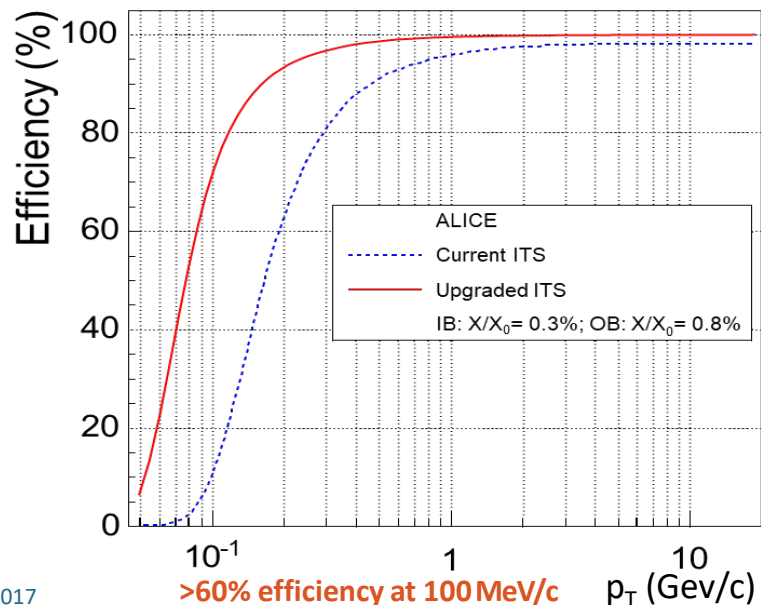
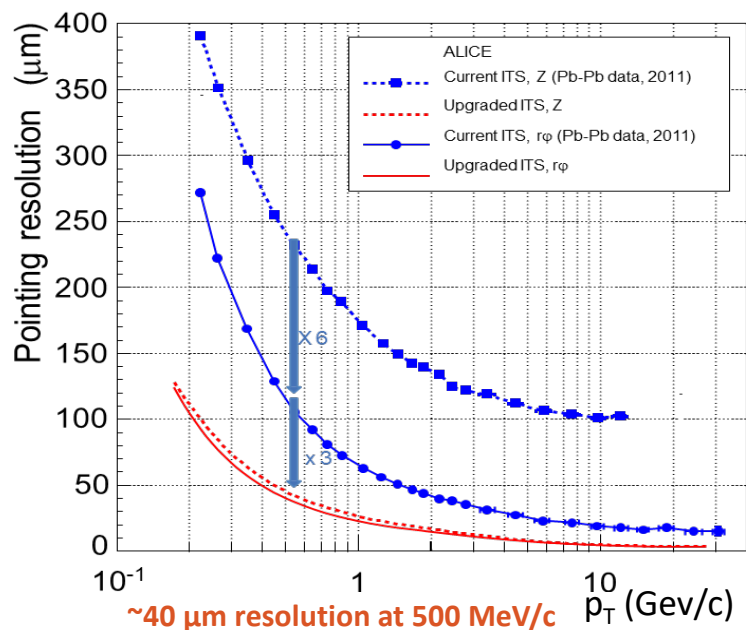
- $r_{\text{in}} = 3.9 \text{ cm}$   $r_{\text{out}} = 43 \text{ cm}$
- 6 silicon detector layers:  
2 hybrid pixel (SPD), 2 silicon drift (SDD), 2 silicon strip (SSD)

SPD thickness ( $X/X_0$ ): **1.14%/layer**  
Readout rate: **~1kHz**



**Major Upgrade of the Inner Tracking System to improve low  $p_T$  tracking and data rate performances**

# ITS UPGRADE KEY REQUIREMENTS



## Improve impact parameter resolution

- Get closer to IP: 1<sup>st</sup> layer 39 mm  $\rightarrow$  23 mm (new beam pipe)
- Reduce material budget:  $1.14\% X_0 \rightarrow 0.3\% X_0$  (Inner Barrel stave)  
Constraints on chip thickness, power density, support structures
- Reduce pixel size:  $50 \mu\text{m} \times 425 \mu\text{m} \rightarrow O(30 \mu\text{m} \times 30 \mu\text{m})$

## Improve low $p_T$ resolution and tracking efficiency

- Pixel, drift, strip detectors  $\rightarrow$  pixel detector
- 6 layers  $\rightarrow$  7 pixel layers

## Improve readout to exploit increased luminosity

- Interactions readout rate (2x LHC expected interaction rate):  
Pb-Pb  $\sim 100\text{kHz}$ , minimum bias

## Capability of fast insertion and removal during end of year shutdown

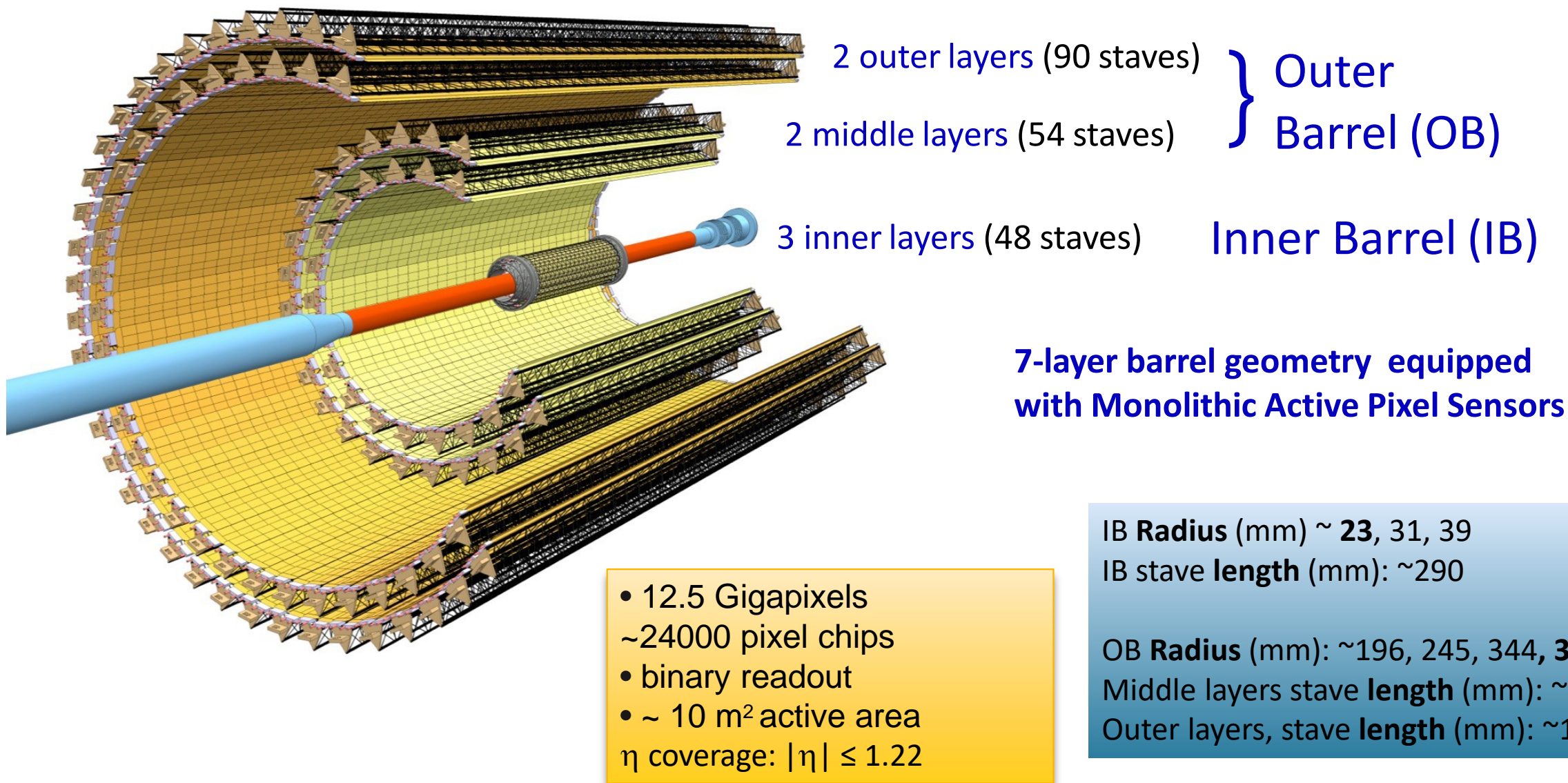
- possibility to replace non-functioning detector modules

## Expected radiation load (10 yrs + safety factor, innermost layer):

- TID:  $\sim 2.7 \text{ Mrad}$ ; NIEL:  $\sim 1.7 \times 10^{13} \text{ 1MeV } n_{\text{eq}} / \text{cm}^2$

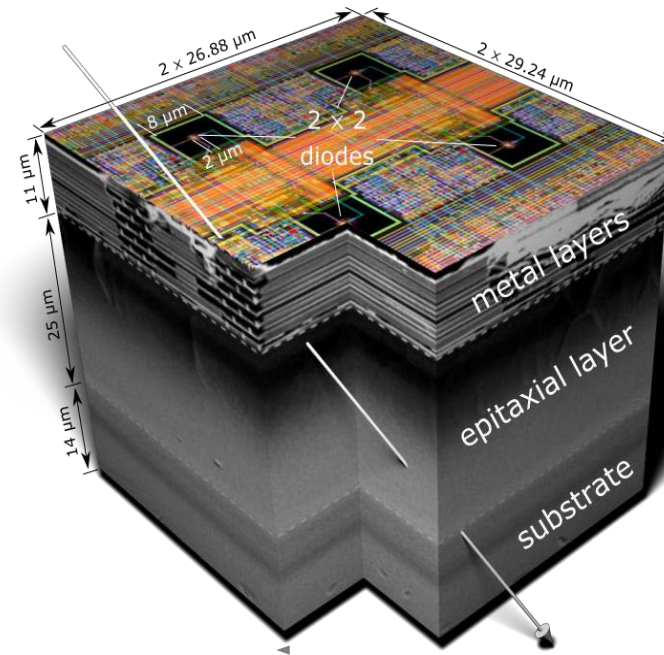
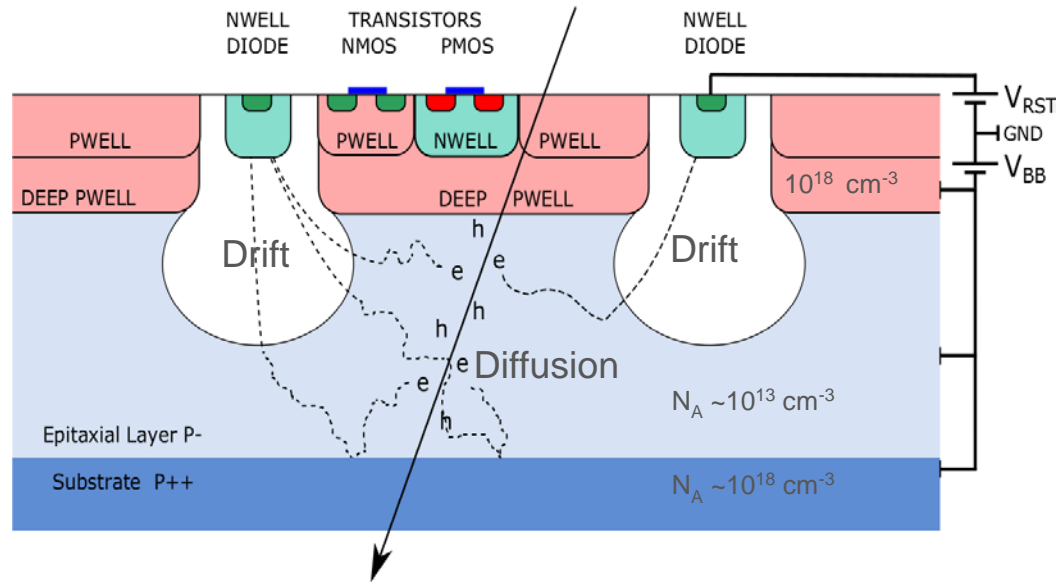


# INNER TRACKING SYSTEM UPGRADE LAYOUT



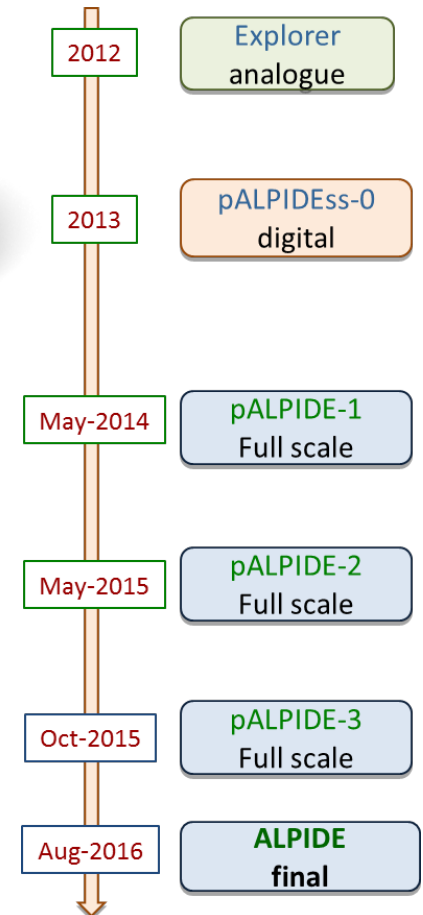
# ALPIDE: THE MONOLITHIC ACTIVE PIXEL SENSOR

## Pixel Sensor produced using TowerJazz 0.18 $\mu\text{m}$ CMOS Imaging Process

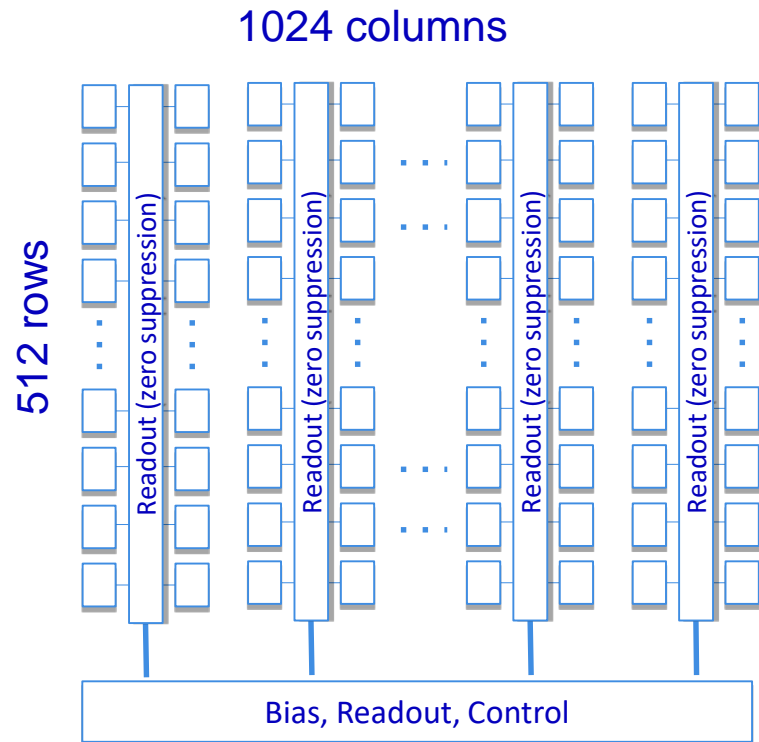


### Pixel sensor R&D

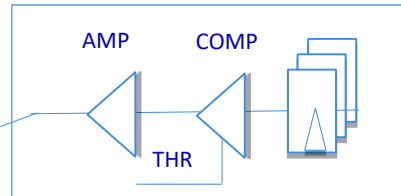
- Deep Pwell allows in-pixel full CMOS (complex in-pixel circuitry without charge loss).
  - Key to enable low-power read-out.
  - High granularity, low material budget ( $\sim 1/7$  w.r.t. present ITS pixel chip)
- Resistivity ( $>1 \text{ k}\Omega\cdot\text{cm}$ ) p-type epitaxial layer ( $25 \mu\text{m}$ );
- Possibility of reverse biasing



# ALPIDE: THE MONOLITHIC ACTIVE PIXEL SENSOR



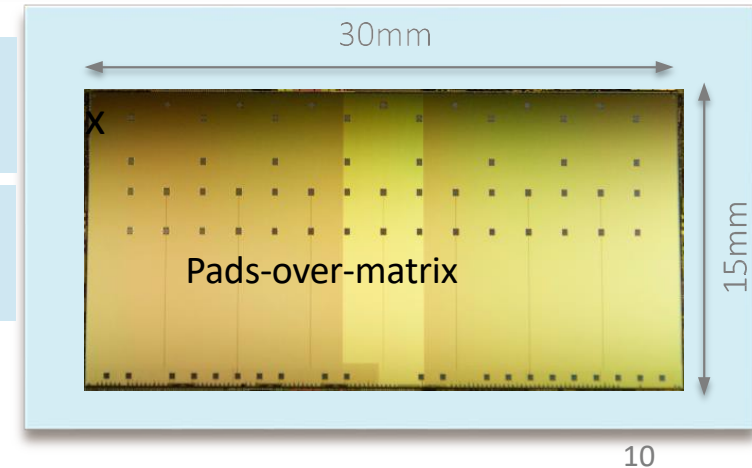
In pixel:



- Amplification
- Discrimination
- multi-event buffer

Chip size:  
30 mm x 15 mm

Pixel size:  
27  $\mu\text{m}$  x 29  $\mu\text{m}$



- In matrix zero suppression.
- Triggered or continuous readout
- Connects directly to 5-m away off-detector electronics via high speed link

Parameter	Inner Barrel	Outer Barrel	ALPIDE
Silicon thickness	50 $\mu\text{m}$	100 $\mu\text{m}$	OK
Spatial resolution	5 $\mu\text{m}$	10 $\mu\text{m}$	$\sim 5\mu\text{m}$
Chip dimension	15mm x 30mm		OK
Power density	< 300mW/cm <sup>2</sup>	< 100mW/cm <sup>2</sup>	< 40mW/cm <sup>2</sup>
Event-time resolution	< 30 $\mu\text{s}$		$\sim 2\mu\text{s}$
Detection efficiency	> 99%		OK
Fake-hit rate *	< 10 <sup>-6</sup> /event/pixel		< 10 <sup>-10</sup> /event/pixel
NIEL radiation tolerance **	1.7x10 <sup>13</sup> 1MeV n <sub>eq</sub> /cm <sup>2</sup>	10 <sup>12</sup> 1MeV n <sub>eq</sub> /cm <sup>2</sup>	OK
TID radiation tolerance **	2.7Mrad	100krad	tested at 500krad

\* revised numbers w.r.t. TDR

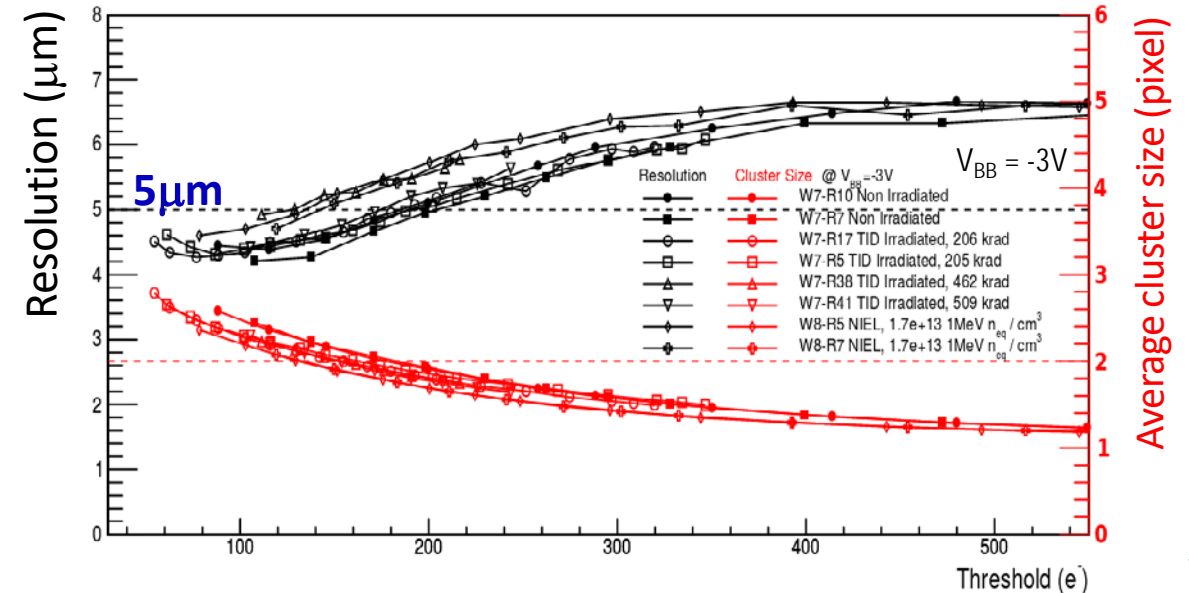
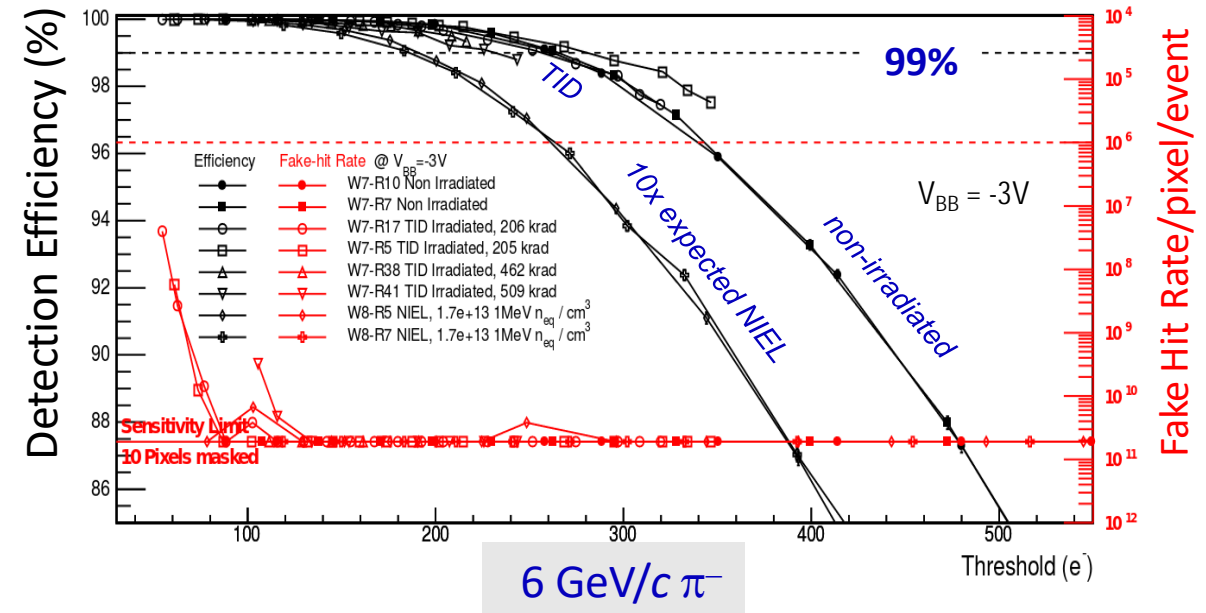
\*\* including a safety factor of 10, revised numbers w.r.t. TDR



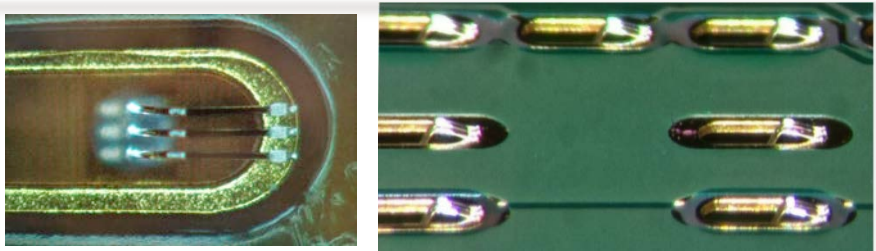
# ALPIDE PROTOTYPES: TESTS AND QUALIFICATION

Extensive chip qualification campaign of laboratory and test beam measurements on irradiated and non irradiated sensors:

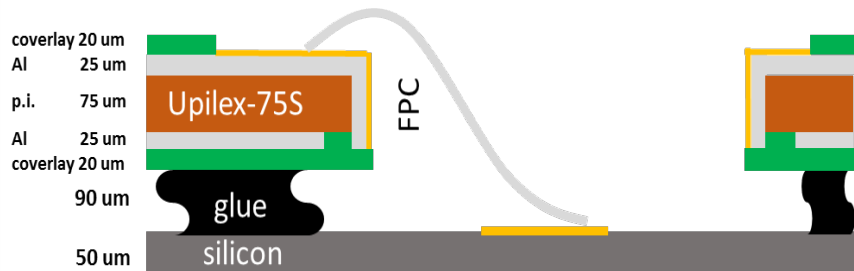
- fake-hit rate  $< 10^{-10}$  /pixel/event ( $10^{-6}$  required)  
→ Big operational margin (only 10 masked pixels)
- Negligible chip-to-chip fluctuations
- Sufficient operational margin after 10x lifetime NIEL dose
- efficiency  $> 99\%$  up to  $\sim 200$  electrons threshold
- Resolution of about  $5\mu\text{m}$  @ threshold of 200 electrons
- **NIEL irradiated chips show no significant degradation of operation margins**



# ITS-UPGRADE HIBRID INTEGRATED CIRCUIT



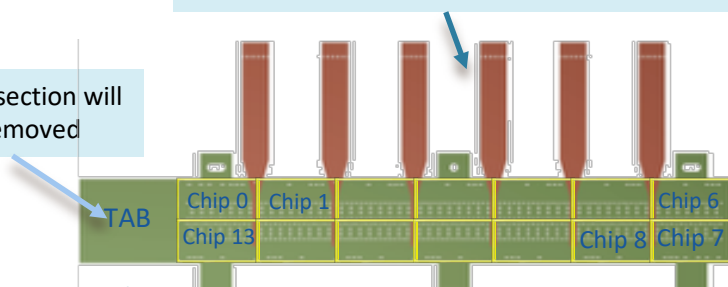
FPC to Chip interconnection



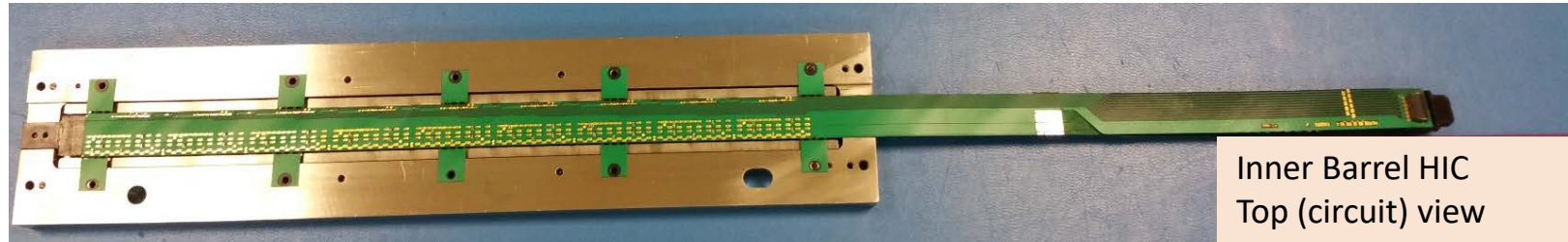
IB HIC cross section scheme

Thin cross cables for later connection to power bus

TAB section will be removed



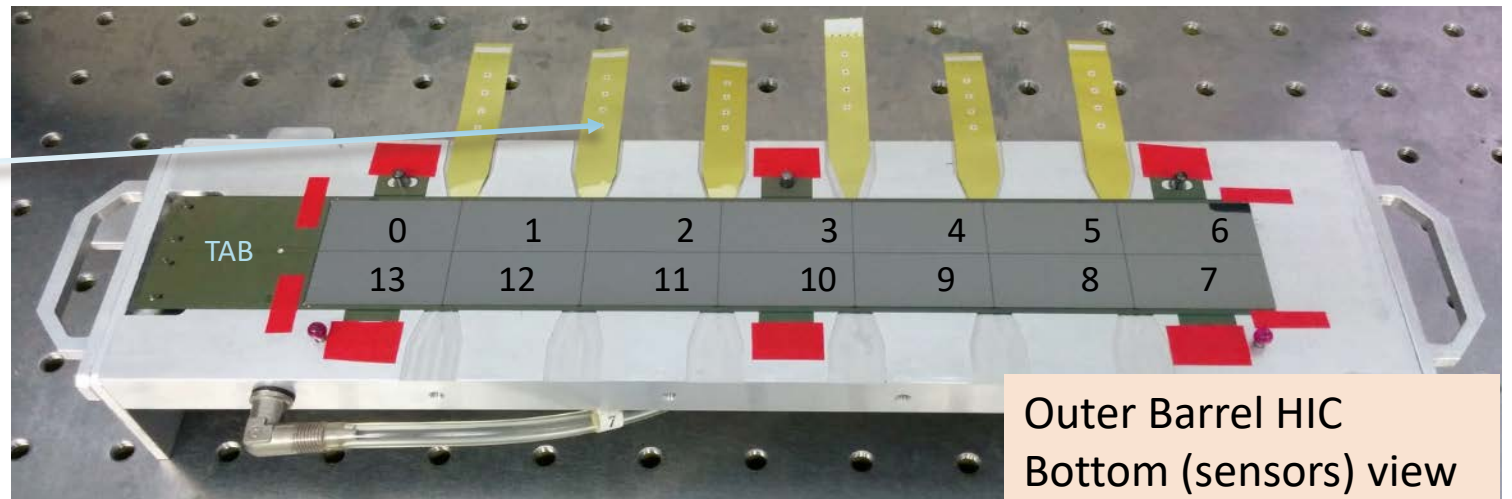
5 -12 July 2017



Inner Barrel HIC  
Top (circuit) view

## Low mass Hybrid Integrated Circuits (HIC)

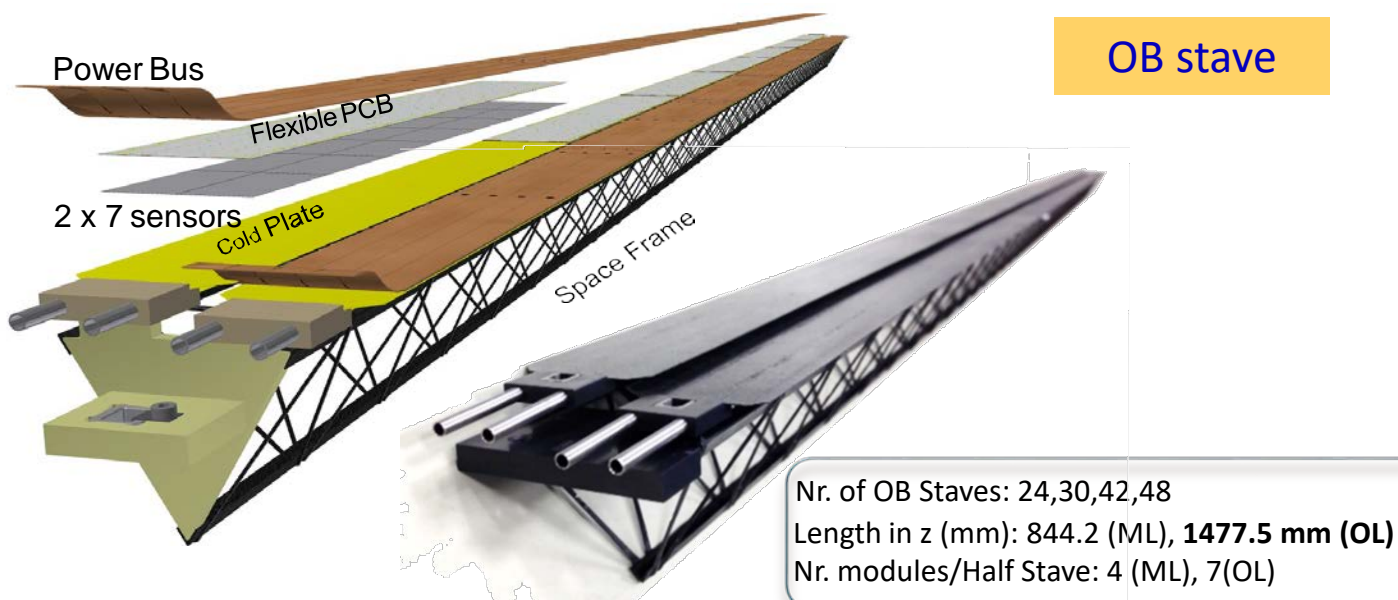
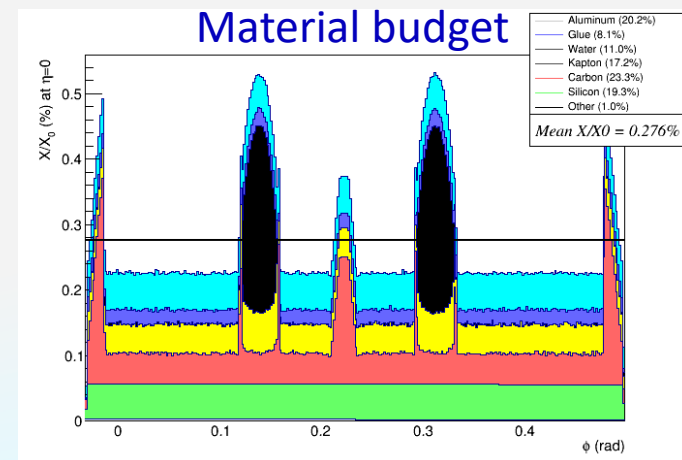
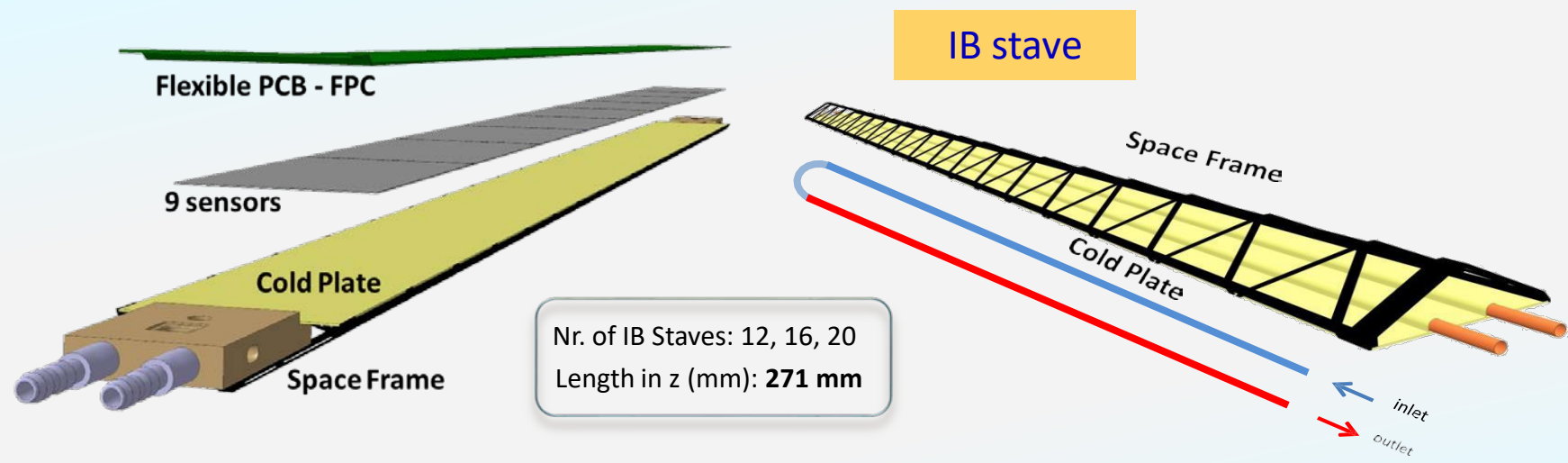
- IB-HIC: 9 master chips (50 um);
- OB-HIC: 2x7 (1 master, 6 slaves) chips (100um)
- IB (OB): double sided Al(Cu)/polyamide Flexible Printed Circuits (FPC)
- Interconnection based on flip chip and wire bonding technology



Outer Barrel HIC  
Bottom (sensors) view



# ITS-UPGRADE STAVES LAYOUT

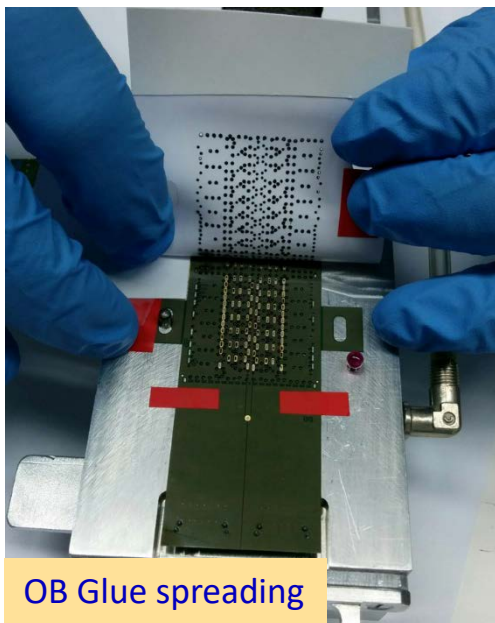


## Staves Material budget

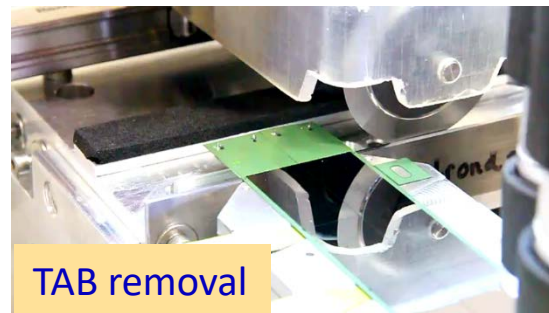
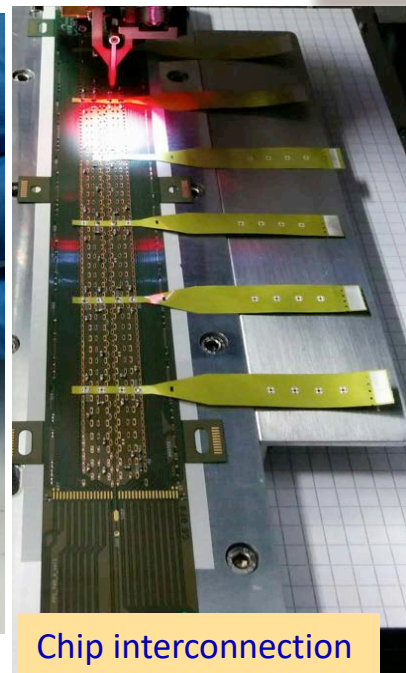
IB:  $\sim 0.3\% X_0$  OB:  $\sim 1\% X_0$

- Ultra-light stiff space frame C structure
- Ultra-light C laminate Cold Plate (with integrated polyimide cooling ducts; single-phase  $H_2O$  coolant)
- Low mass Hybrid Integrated Circuit

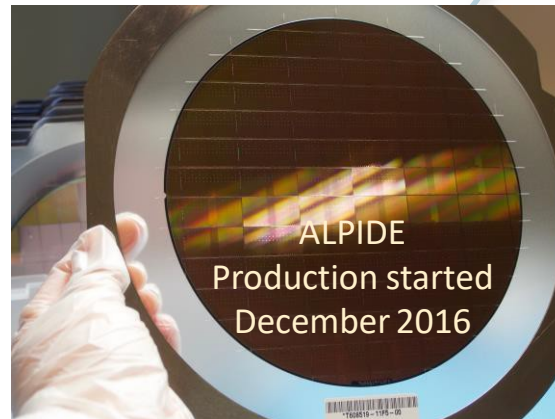
# HIC, STAVE, MECHANICS ASSEMBLY AND PRODUCTION



HIC assembly

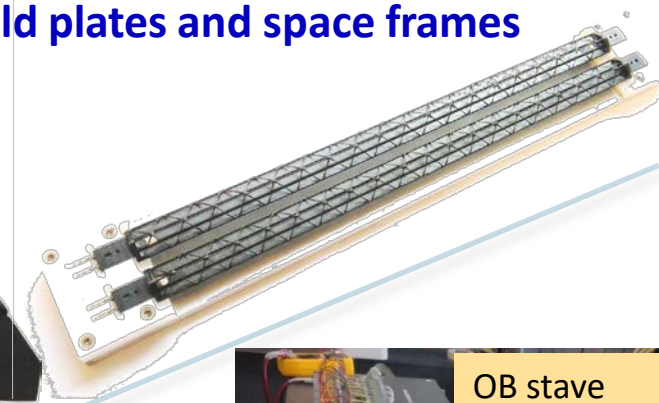


HIC Preparation  
for assembly

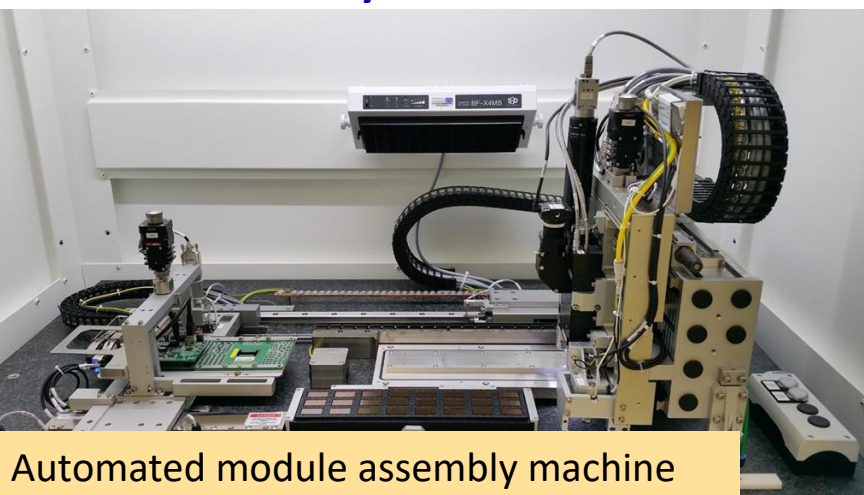


IB and OB  
staves assembly

Staves production:  
Cold plates and space frames

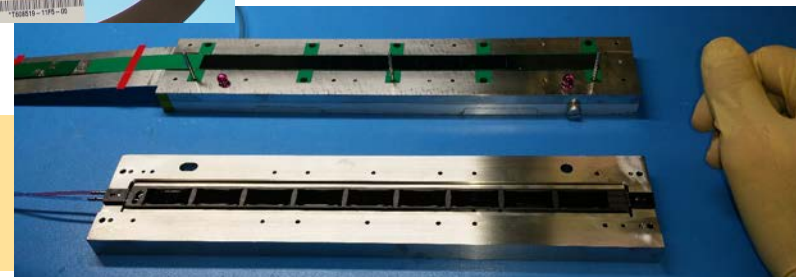


OB stave  
assembly



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IB Space  
Frame + HIC  
gluing

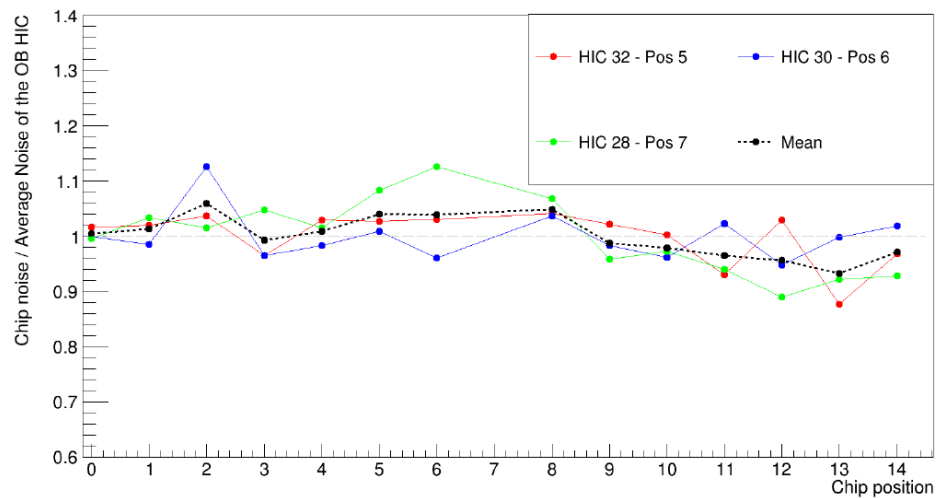




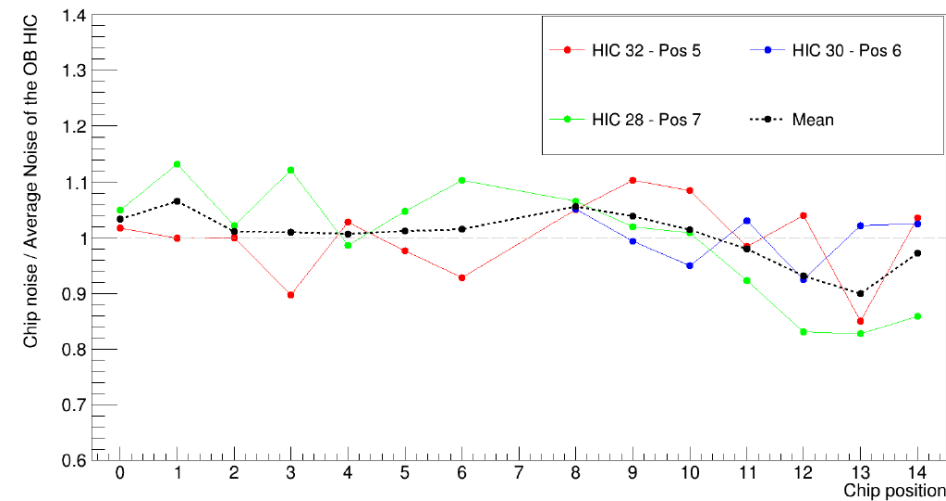
## HICs and Staves prototypes

- HICs were characterized in different conditions, operation modes and readout rates
- No significant difference in performance found between standalone chip and chip mounted on HIC
- No significant difference in performance found between HICs and HICs mounted on staves.
- **All performances comparable to standalone ALPIDE chip**

Noise/Average noise-- before mounting



Noise/Average noise-- after mounting

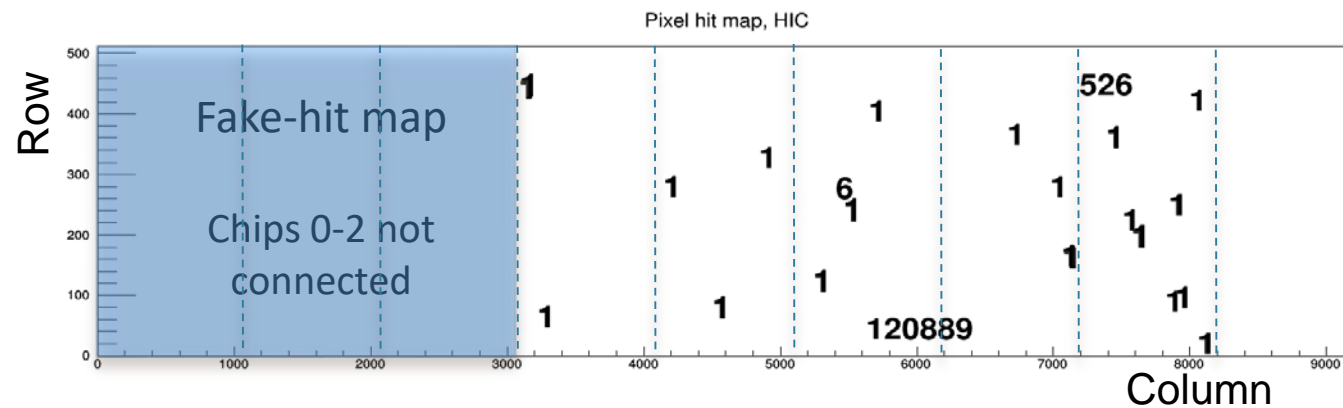




# HICS AND STAVES PROTOTYPES CHARACTERIZATION

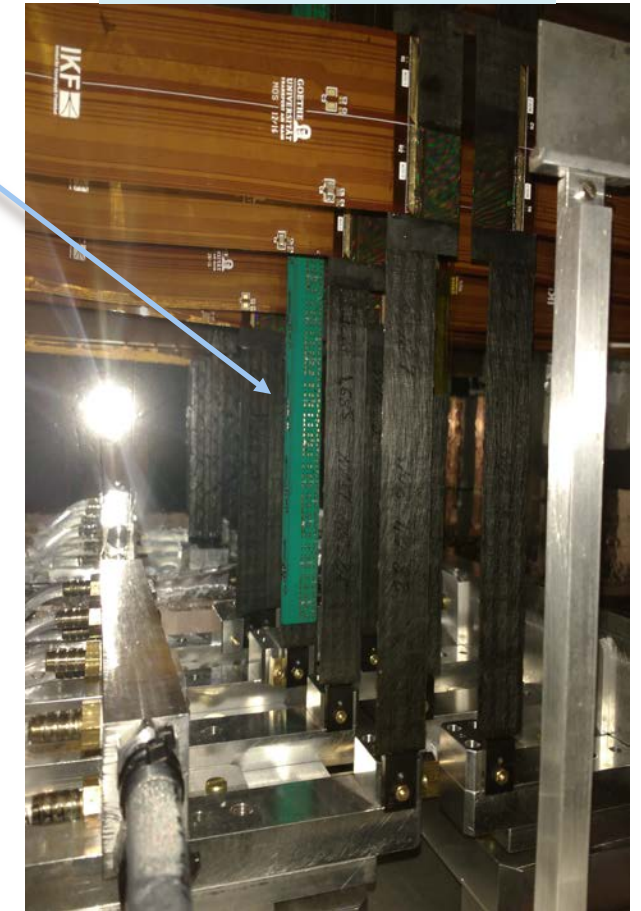
## IB stave tested in Pb-Pb run in NA61/SHINE experiment

- Hit densities: up to 30 hits/cm<sup>2</sup> (realistic Pb-Pb ALICE running conditions)
- No cooling, no substrate reverse-bias used.
- Fake hit rate < 10<sup>-10</sup> hits/pixel/event (10 pixels masked)
- Detection efficiency: >99%
- Performance comparable to standalone ALPIDE chip

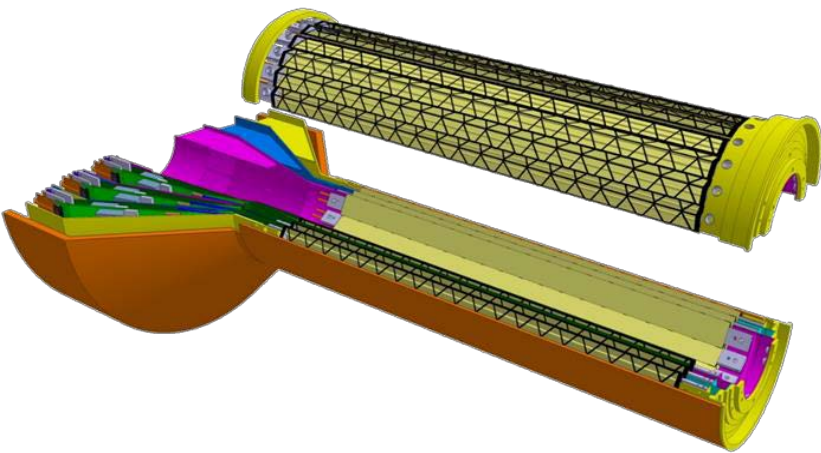


IB HIC in NA61 setup

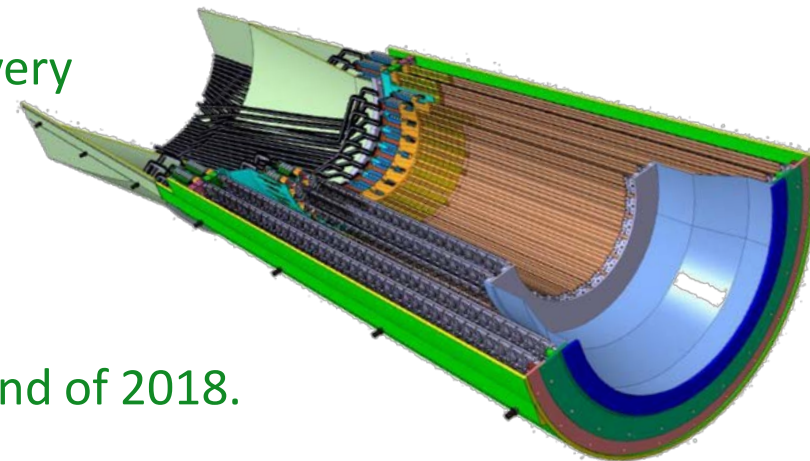
IB-HIC



# CONCLUSIONS



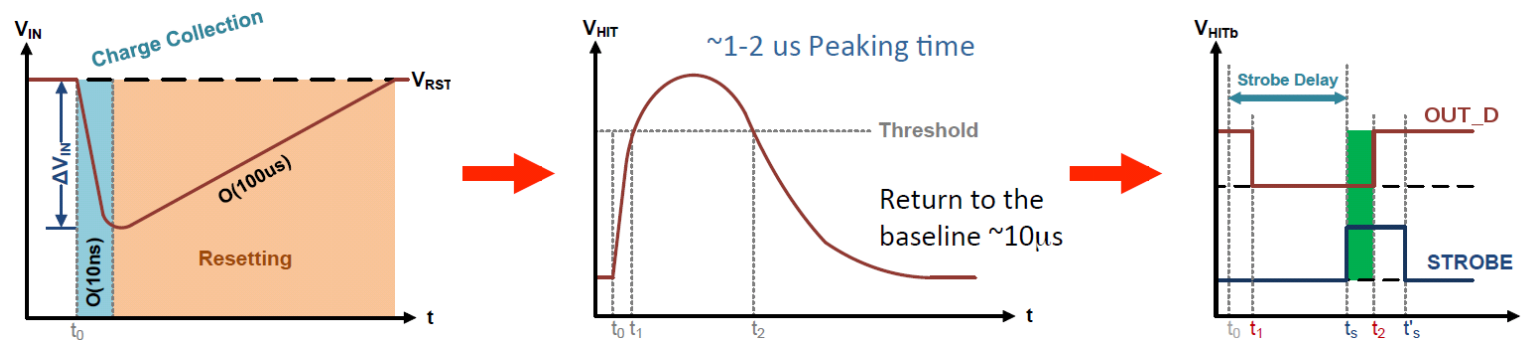
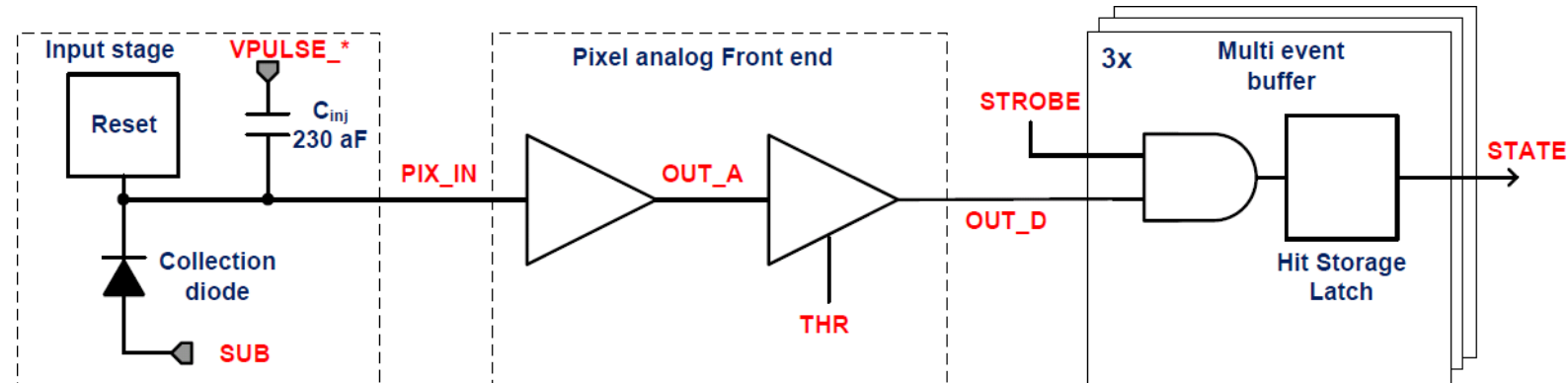
- The ALICE collaboration will perform a major detector upgrade during LS2 to improve readout and tracking capabilities for runs 3&4 at LHC.
- The ALICE Inner Tracking System Upgrade project has successfully completed the R&D phase. All requirements have been met or exceeded.
- The ITS Upgrade will be the largest existing pixel detector with an innovative monolithic pixel sensor with in pixel full CMOS circuitry.
- Detector production started Dec 2016 with the ALPIDE chip start of production.
- Fabrication of staves and barrel mechanics and cooling structures in a very advanced stage.
- HIC production is starting.
- All sites are entering the production phase, expected to finish by the end of 2018.



# SPARE SLIDES



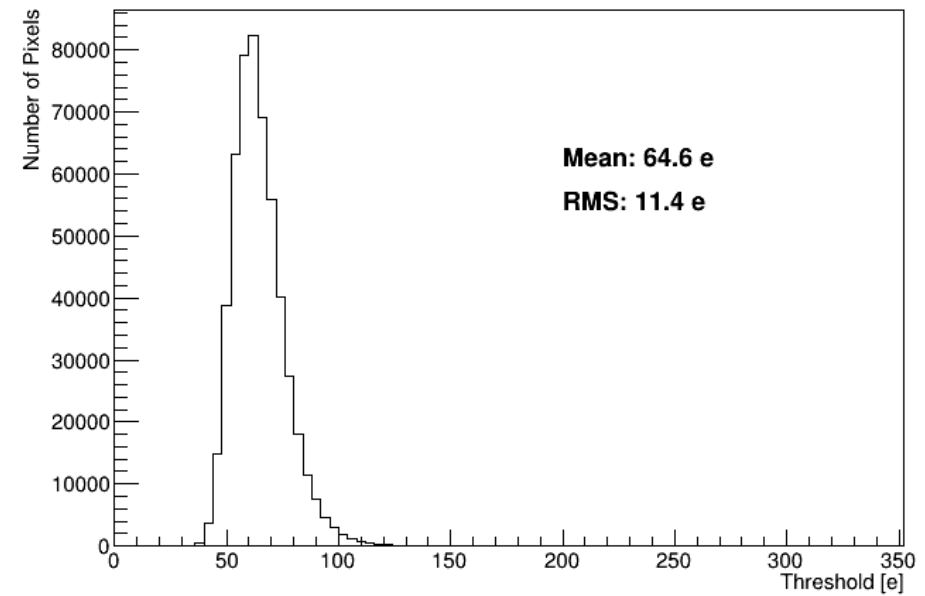
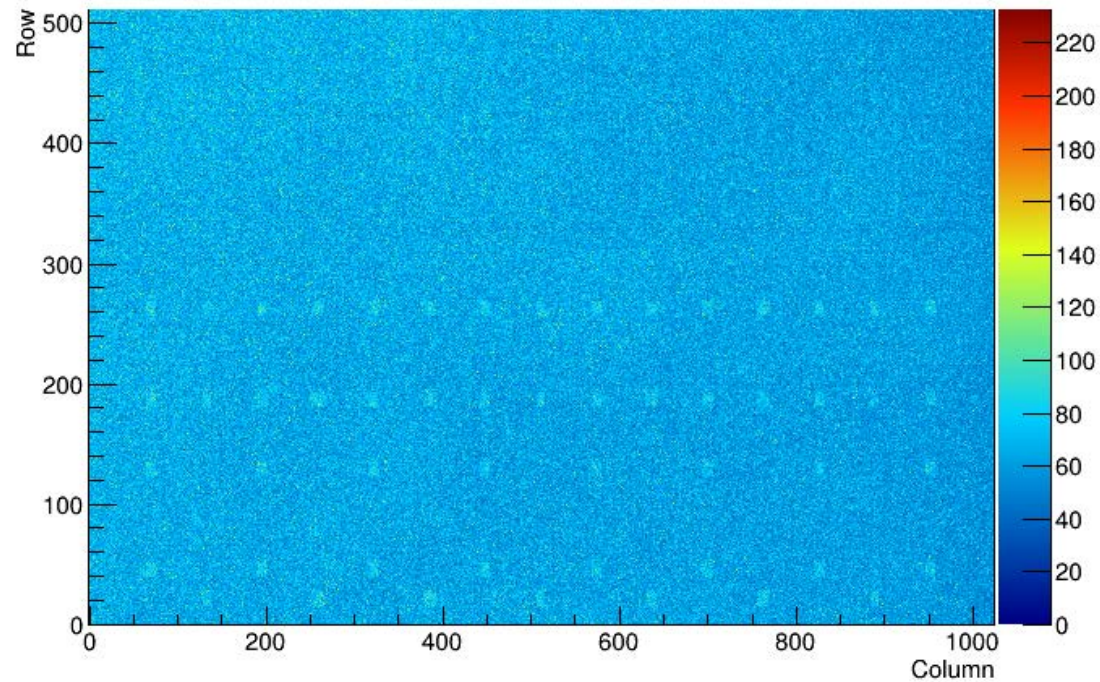
# PIXEL



- Charge generated in epitaxial layer is collected
- Signal is shaped and compared to threshold
- Signal is strobed (global shutter) into an in-pixel memory (3 hit storage register)
- Hit pixels are read out asynchronously (priority encoding)

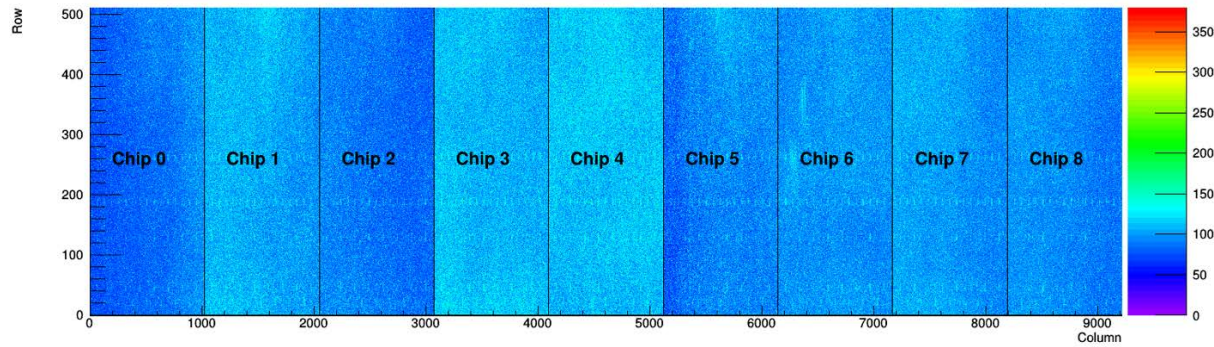
# SINGLE CHIP THRESHOLD SCAN

- Example of thresholds from S-curve scans (obtained with charge injections)



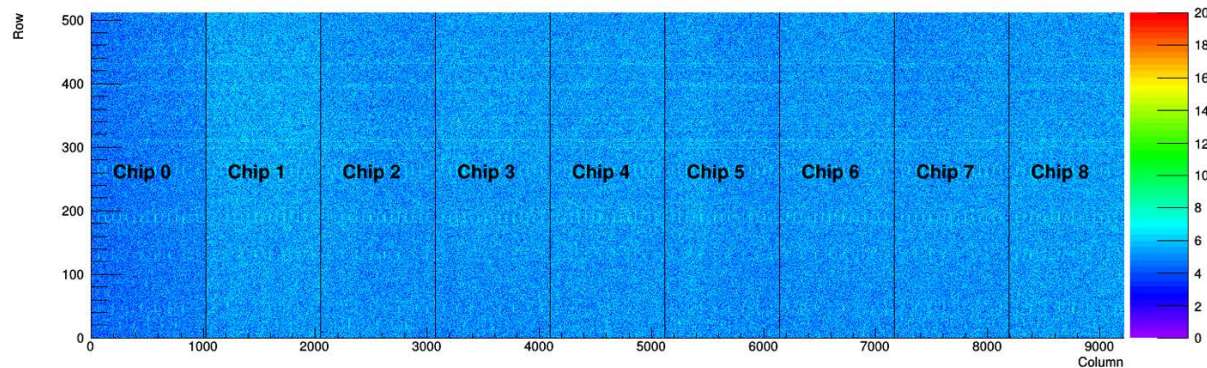
# HIC THRESHOLD AND NOISE SCANS

Threshold scan



- Example of threshold and noise scans of an Inner Barrel HIC
- Chip-to-chip fluctuations comparable to single chips

Noise scan





# OVERALL ITS PLANNING

